IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	James W. Adkisson, et al	**Examiner:**	Unassigned
Serial No.:	/0/7/0642	**Group Art Unit:**	
Filed:	7-27-04	**Docket:**	BUR920030194US1 (17344)

For: DESIGNING SCAN CHAINS WITH SPECIFIC   **Dated:**   May 10, 2004
PARAMETER SENSITIVITIES TO IDENTIFY
PROCESS DEFECTS

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the

following references, which are also listed on the attached Form PTO-1449, be made of

record in the above-identified case.

Applicants are submitting copies of the cited references, along with an English

Abstract which explains the pertinence of the reference.

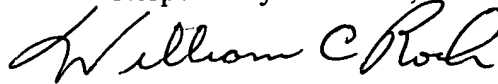## CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.8(a)

I hereby certify that this correspondence is being deposited with the United

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Patents, Box 1450, Alexandria, VA 22313-1450 on_____7-30-04_____.

Dated:_____7-30-04_____

P. L. de LANGIS

Inasmuch as this Information Disclosure Statement is being submitted in

accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.
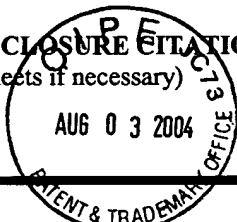
Respectfully submitted,

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Docket Number (Optional)
BUR920030194US1 (17344)

Application Number
10/710642

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7-27-04

Group Art Unit
Unassigned

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

AUG 0 3 2004

Applicant(s)

James W. Adkisson, et al

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
		EP146661A1	12/16/86	EPO				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		At-Speed Test Is Not Necessarlily An AC Test, by Jacob Savir and Robert Berry, Int'l Test Conf. 1991.
		IBM Technical Disclosure Bulletin 8-86 P. 1234-1236, Measuring Process-Induced AC Chip Performance Variations Using SRLs.
		IBM Technical Disclosure Bulletin 3-88 P. 288, Process Monitoring For LSSD Designs.

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820
(also form PTO-1449)

P09A/REV04

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